

I: The Microscope

II: The Specimen

III: The Structure

Reading assignment: Lecture notes pp.1-38

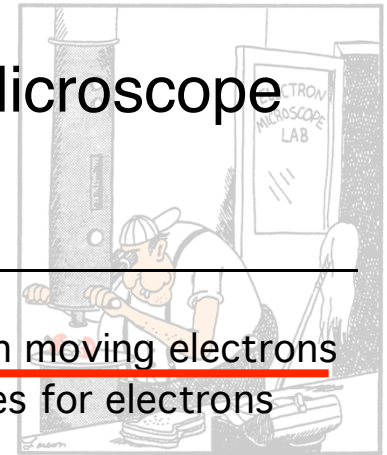
# § I: The Microscope

I.A Principles of TEM

I.A.1 Origin of the Electron Microscope

(page 1 of lecture notes)

# I.A.1 Brief History of the Transmission Electron Microscope



DATE	NAME/COMPANY	EVENT
★ 1897	J. J. Thompson	Discovered the <u>electron</u>
★ 1924	Louis deBroglie (as grad student)	Identifies <u>wavelengths associated with moving electrons</u>
1926	H. Busch	Magnetic or electric fields act as lenses for electrons
★ 1929	E. Ruska	<u>Ph. D thesis on magnetic lenses</u>
1931	Davisson & Calbrick	Properties of electrostatic lenses
★ 1932	M. Knoll & E. Ruska	<u>First electron microscope built (prototype of modern microscopes)</u>
★ 1935	E. Driest & H. Muller	<u>Surpass resolution of the LM</u>
1938	B. von Borries & E. Ruska	Constructed TEM capable of resolving 10 nm (= 100 Å)
1939	Siemens	First practical TEM
★ 1941	RCA	<u>Commercial TEM with 2.5 nm resolution</u>
1946	J. Hillier	1.0 nm resolution achieved



**RCA announces revolutionary NEW Electron Microscopes**

—the ideal tool for advanced research's highest resolution, accurate magnetic optical control. The RME-1A, a 20,000 electron, has every important feature in peak performance in a wide range of new optical functions.

Here are some of the key engineering and improvements that make these instruments available:

- High resolving power—20 and 30 Angstroms
- Consistently high resolution—most 10,000 Angstroms
- Choice of 10,000 volt and 10,000 volt as primary
- Partial electron counter for stability
- High set of pole pieces for all magnification
- Removable objective and magnetic field coils and plate camera—choice of fast film area
- External control of objective aperture
- Electronic Tracer
- Large 2" x 2" slow view, high brightness
- Fast Motion Control—Control speed of Selected Area and Reflection Diffraction

**What can these important instruments do for you?**

Partial information on the features, use and operation of the revolutionary RME-1A Electron Microscope is given in the White Paper: Radio Corporation of America, P.O. Box 111, Building 1-1, Camden, N. J.

**RCA** RADIO CORPORATION OF AMERICA

## A Few Ground Rules

- TEM is not simply “knob twiddling”
  - To be “good”, need to understand basic principles
  - TEM relies on many basic principles (mostly physics)
  - Some concepts may not make much sense at first...but **HANG IN THERE!** (review and re-review the concepts so they become 2<sup>nd</sup> nature to you)
- Goal:** Even if you don't aspire to be a practicing electron microscopist, at least you can view published work with a critical ‘eye’

**KEY CONCEPT:**

**Electrons** and **photons** have common properties

For example, they are both used to **form images**

# § I: The Microscope

I.A Principles of TEM

I.A.2 Comparison of Light and Electron Microscopes

(pp.1-7 of lecture notes)

## I.A.2 Comparison of Light and Electron Microscope



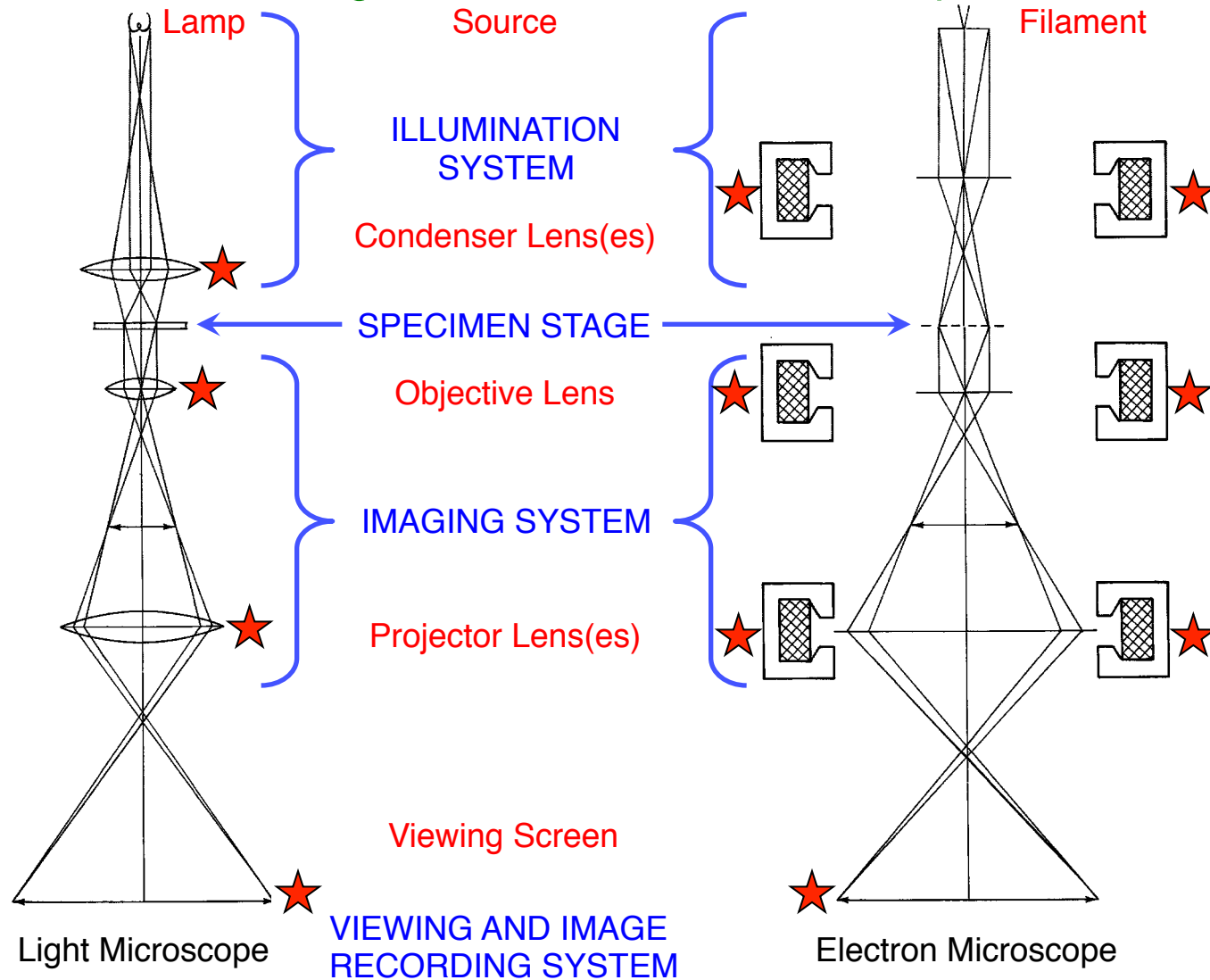
## I.A.2 Comparison of Light and Electron Microscope





# I.A.2 Comparison of Light and Electron Microscope

Similar arrangement and function of components



## I.A.2 Comparison of Light and Electron Microscope

# SIMILARITIES

Similar arrangement and function of components

**ILLUMINATION SYSTEM:** Radiation source & condenser lens

Source produces illumination beam

Condenser focuses beam on specimen

**SPECIMEN STAGE:**

Hold specimen between illumination & imaging systems

**IMAGING SYSTEM:** Objective and projector lenses

Objective produces first (intermediate) image

Projector(s) magnifies a portion of the intermediate image to form final image

**IMAGE RECORDING SYSTEM:** Photographic emulsion (film) or CCD or  
DDD camera

Converts radiation into a 'permanent' image

# I.A.2 Comparison of Light and Electron Microscope

## DIFFERENCES

### Light Microscope

- Optical lenses  
**Glass; fixed** focal length
- Magnification changes  
Switch objective lens or ocular (eyepiece)
- Depth of field small  
**Different** focal levels in specimen
- Mechanism of image formation  
Mainly **amplitude** (scattering) contrast

### Electron Microscope

- Magnetic lenses  
**Ferromagnetic** materials & windings of copper wire  
**Variable** focal length (vary current)
- Magnification changes  
Objective lens focal length '**fixed**'  
Projector focal length varied
- Depth of field large  
**Entire** (thin) specimen is **in focus**
- Mechanism of image formation  
Mainly **phase** (interference) contrast

# I.A.2 Comparison of Light and Electron Microscope

## MORE DIFFERENCES

### Light Microscope

### Electron Microscope

#### - Specimen Environment -

Nothing unusual

**High vacuum** ( $10^{-6}$  -  $10^{-7}$  Torr)  
Specimen *usually* **dehydrated** (dead!)

#### - Beam Effects -

None

Biological specimens **rapidly damaged**

#### - Magnification/Resolution -

~1000X or less

~ 10,000 to 100,000X or more

~0.1  $\mu\text{m}$  or worse

~ 0.3 nm (0.003  $\mu\text{m}$ ) or better

#### - Orientation of Components -

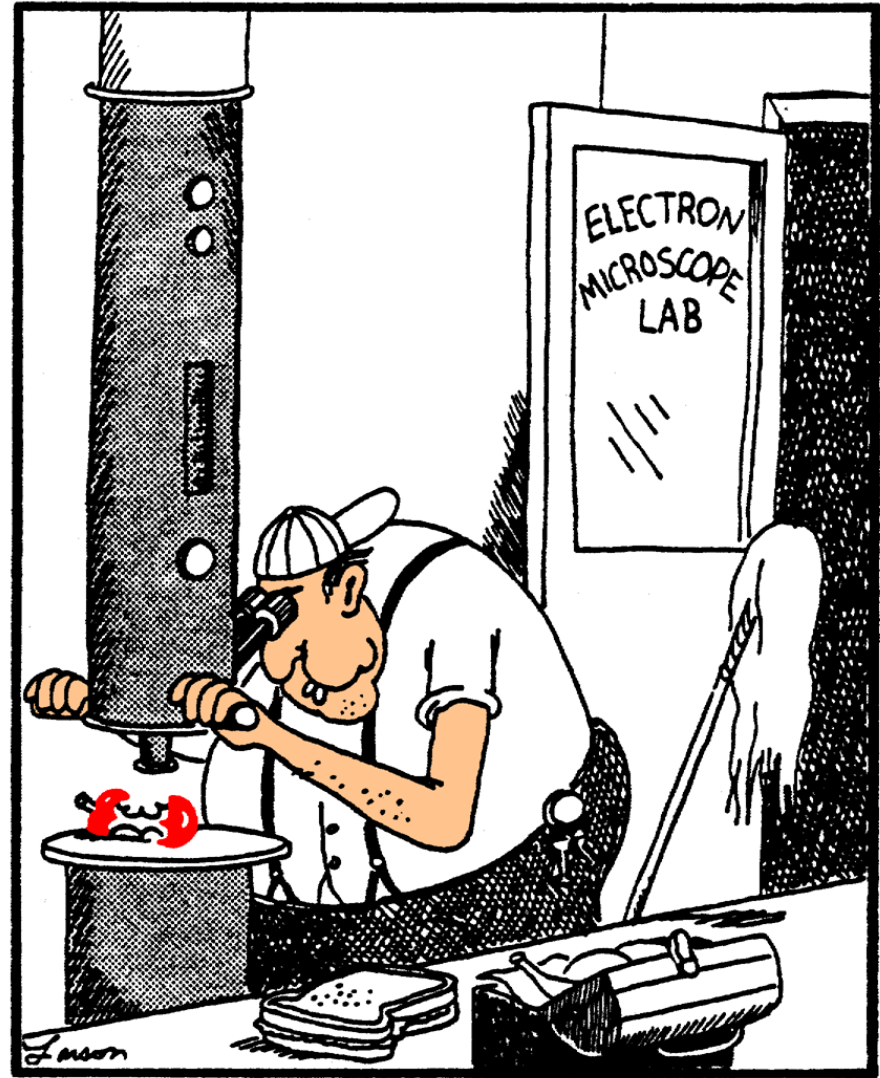
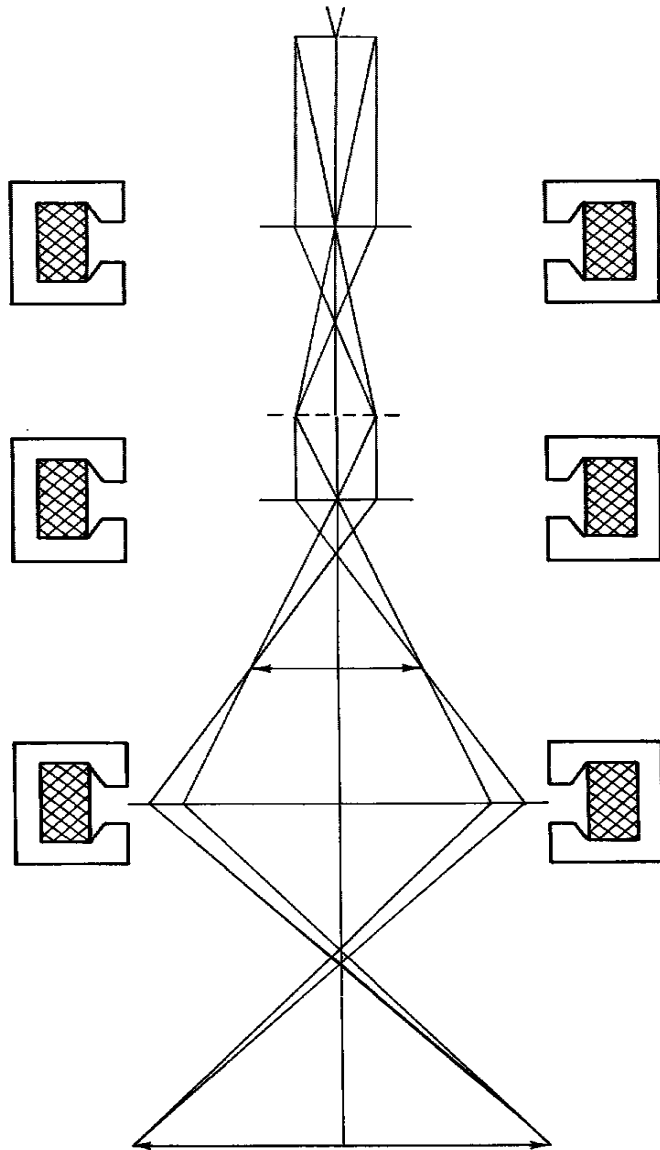
Radiation source generally at **bottom**

Radiation source at **top**

#### - Price Tag -

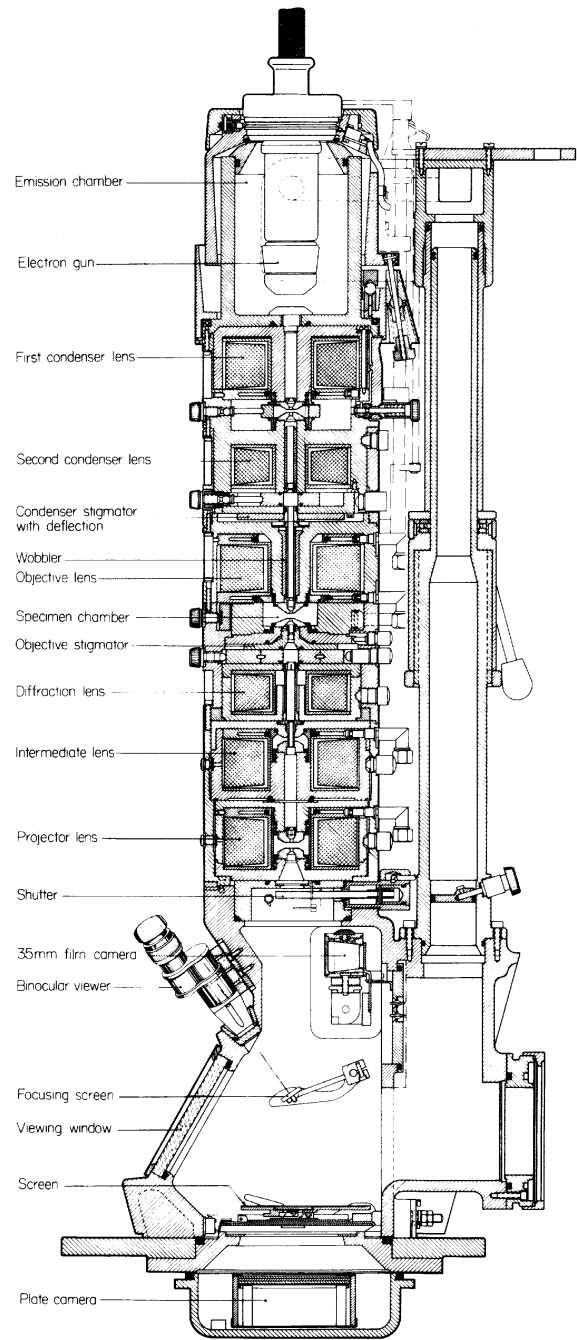
\$1000s (not confocal)

\$400,000 -> \$5,000,000 or more!!!



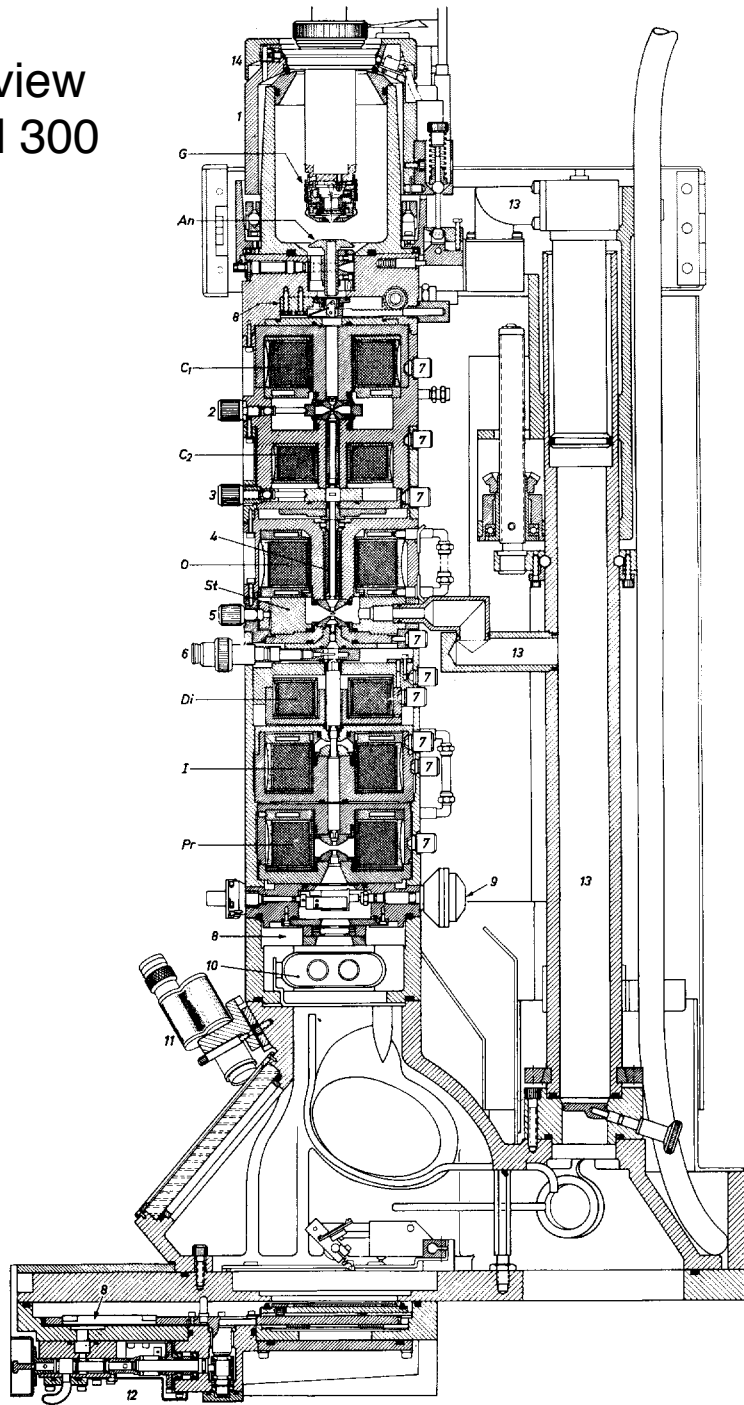
Electron Microscope

# Cross-sectional view of the Philips EM 200



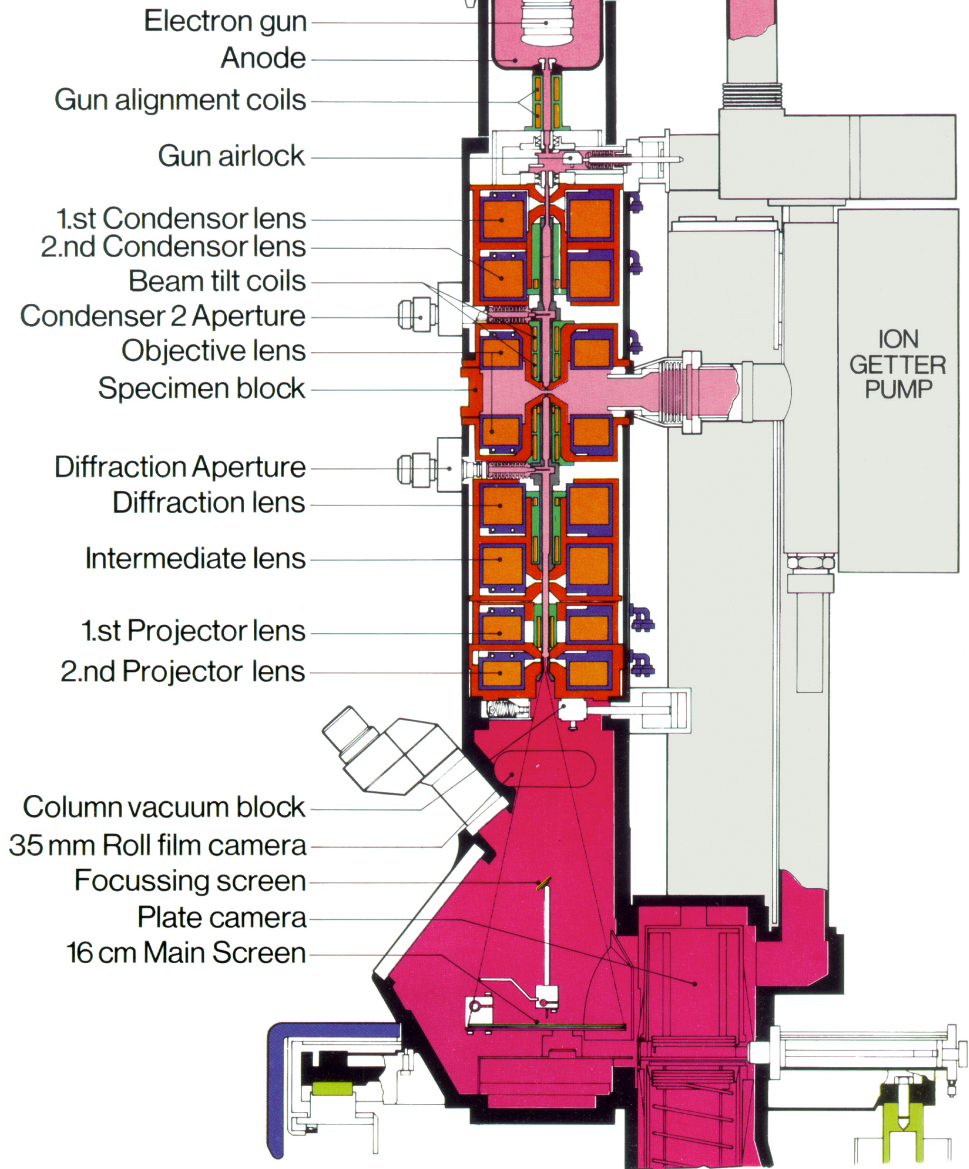
From Meek, Fig. 5.4b, p.99

Cross-sectional view  
of the Philips EM 300



From Agar, Fig. 2.2, p.40

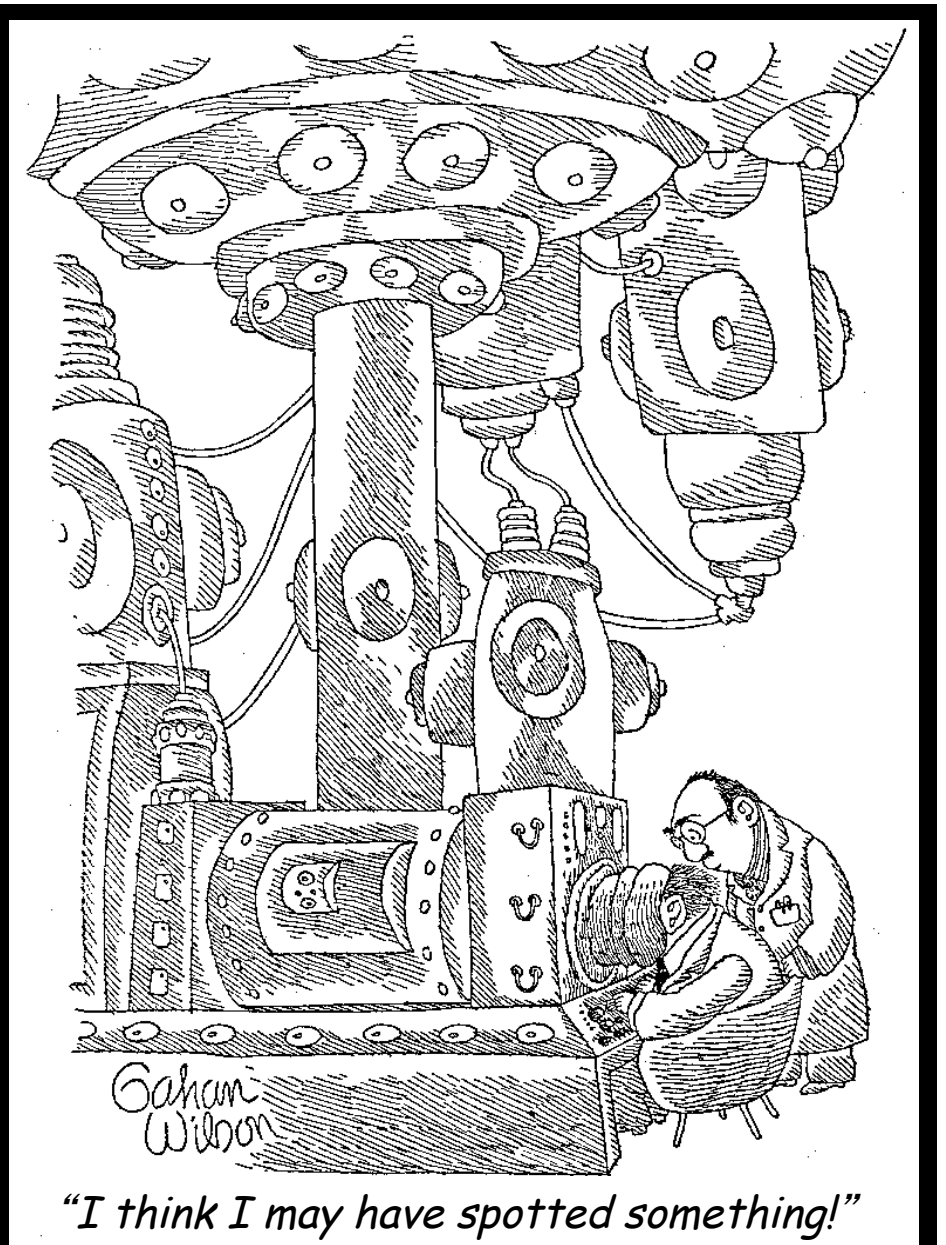
# Cross-sectional view of the Philips EM 400





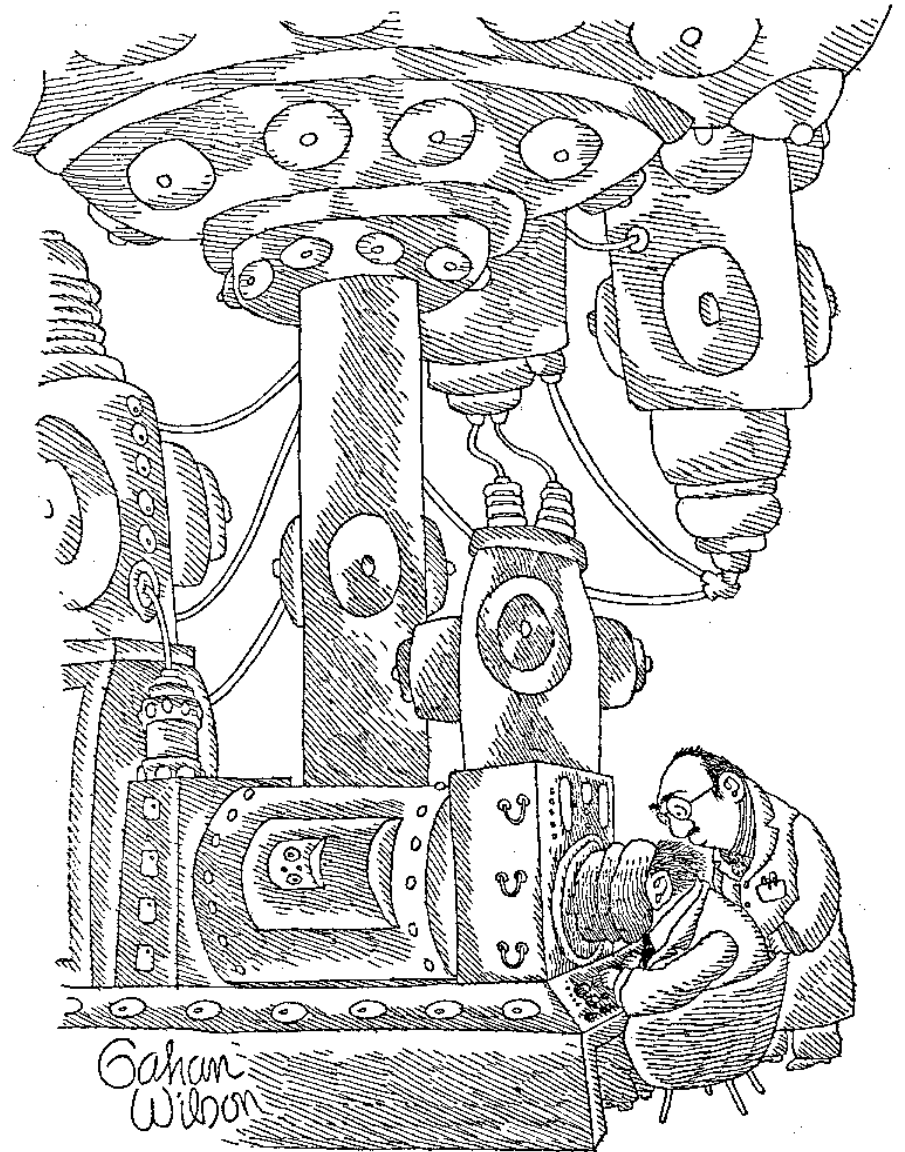


FEI Tecnai Polara 300kV, Helium stage





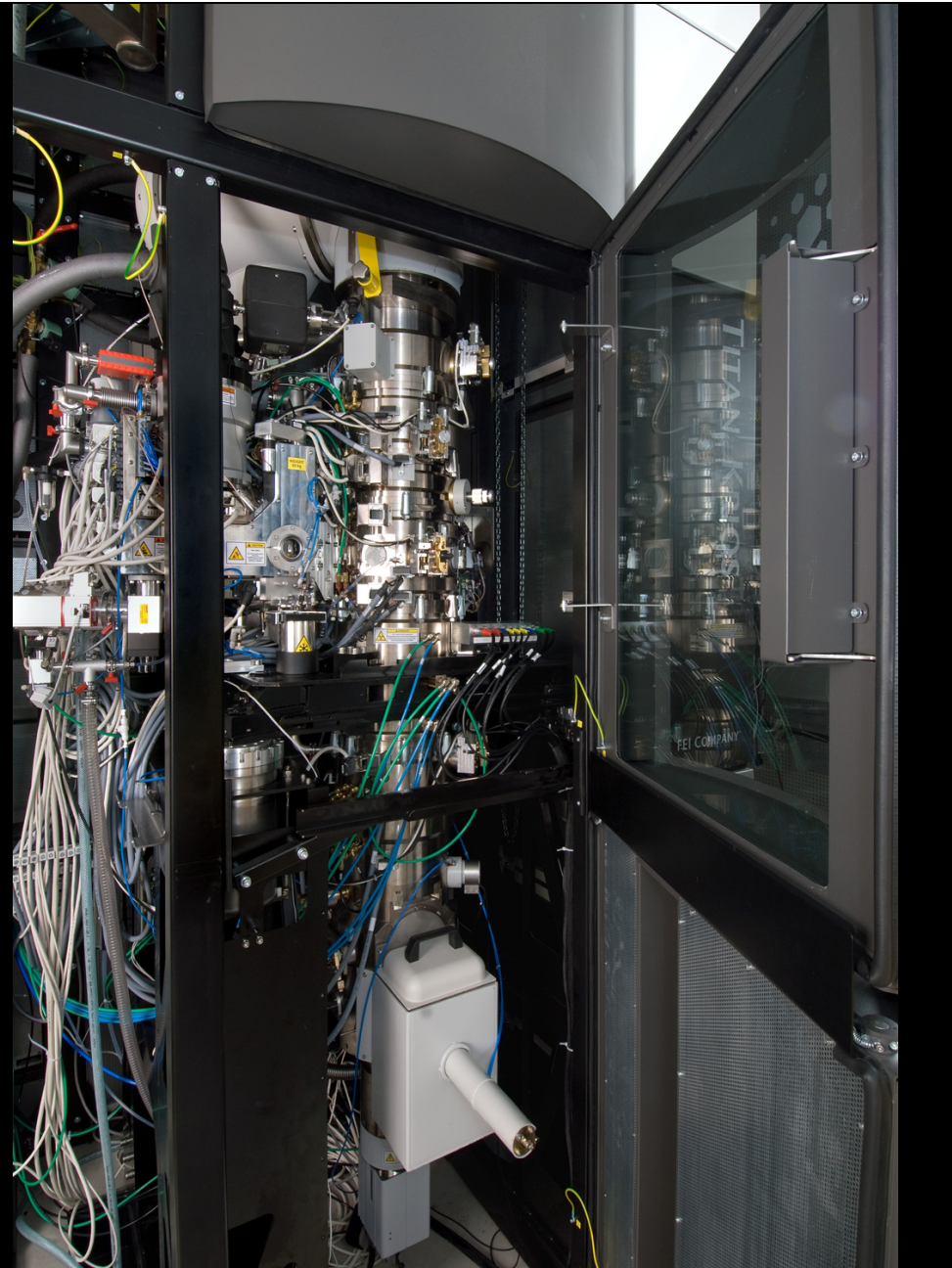
FEI Titan 80-300kV



*"I think I may have spotted something!"*



FEI Titan 80-300kV



FEI Titan 80-300kV

# § I: The Microscope

I.A Principles of TEM

**I.A.3 Photons/Electrons**

(pp.7-16 of lecture notes)

## I.A.3 Photons/Electrons

### KEY CONCEPTS

- Photons **and** electrons behave as particles **AND** waves
- **Any** moving particle has a **wavelength** associated with it
- **TEM: electrons** travel **very fast** (near speed of light) and have **very short** wavelengths
- **Diffraction:** path of radiation is bent by ‘obstacles’

## I.A.3 Photons/Electrons

### I.A.3.a Dual Concept of Wave and Particle

**Light** (photons) has both **particle and wave** properties

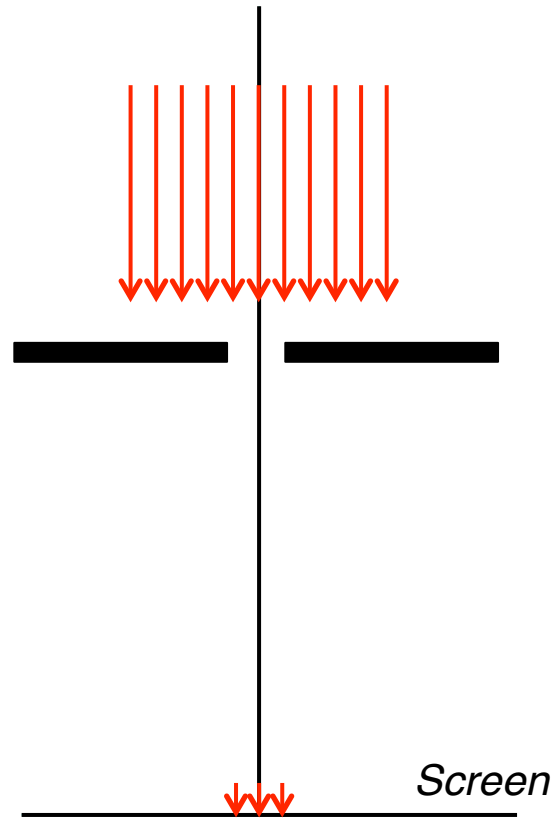
**Electrons** also exhibit **particle and wave** properties

**Diffraction** of light and electrons illustrates their **wave nature**

Diffraction refers to the **bending of the path** of radiation by  
'obstacles'

## I.A.3 Photons/Electrons

### I.A.3.a Dual Concept of Wave and Particle

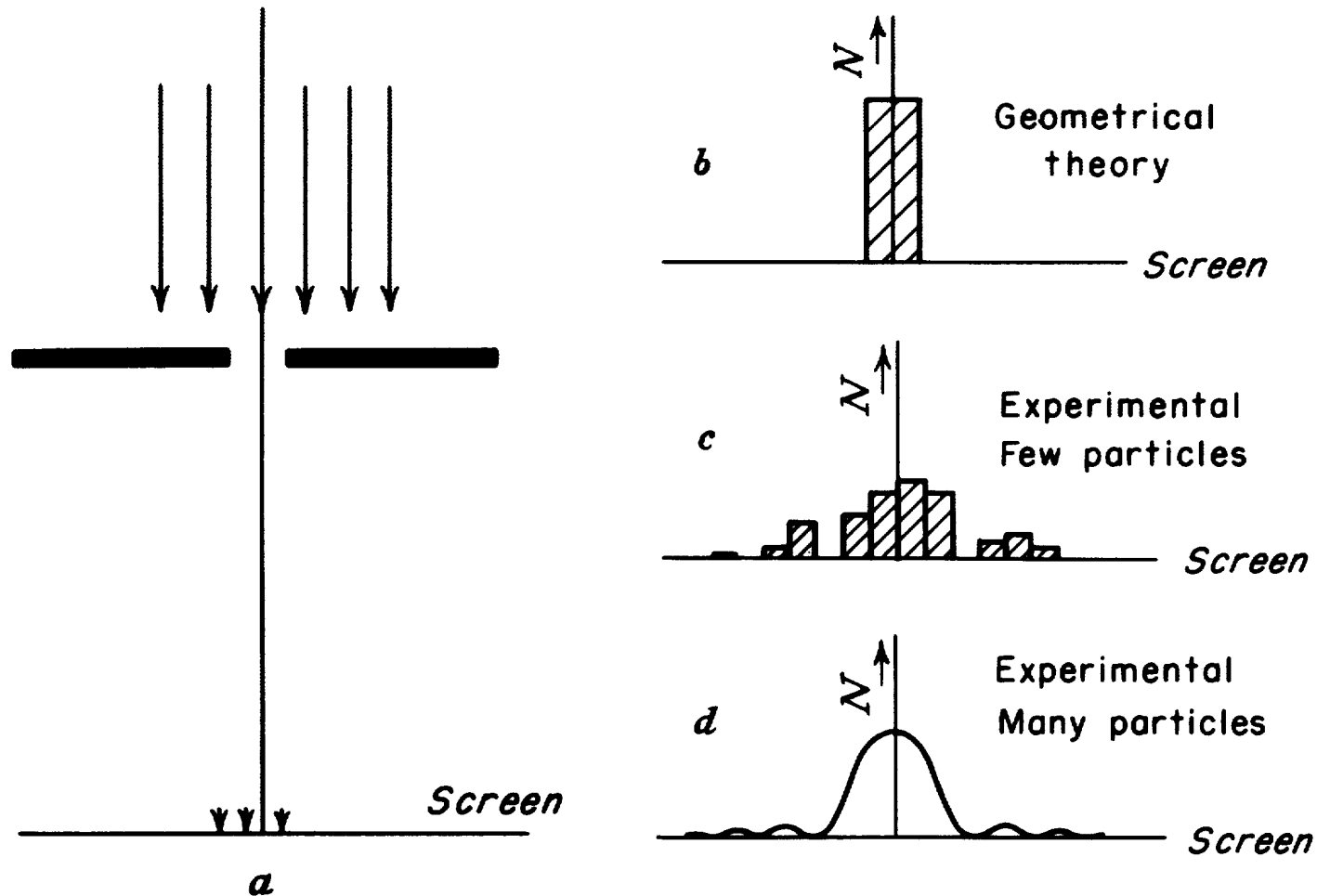




# I.A.3 Photons/Electrons

## I.A.3.a Dual Concept of Wave and Particle

### Statistical Nature of Diffraction Patterns



## I.A.3 Photons/Electrons

### I.A.3.b Electron Velocity and Wavelength



DeBroglie (1924):

A particle of mass,  $m$ , moving at a velocity,  $v$ , has a **wavelength** ( $\lambda$ ) given by:

$$\lambda = \frac{h}{mv}$$

DeBroglie wave equation  
( $h$  = Planck's constant)

Wavelength decreases as velocity increases

## I.A.3 Photons/Electrons

### I.A.3.b Electron Velocity and Wavelength

$$\lambda = \frac{h}{mv}$$

DeBroglie wave equation  
( $h$  = Planck's constant)

$$\frac{1}{2}mv^2 = eV$$

Kinetic energy of moving electron  
( $e$  = electron charge;  $V$  = voltage)

$$v = \sqrt{\frac{2eV}{m}}$$

Solve above for velocity of electron

$$\lambda = \left(\frac{h}{m}\right) * \frac{1}{\sqrt{\frac{2eV}{m}}} = \sqrt{\frac{h^2}{2meV}}$$

$\lambda$  inversely related to  $1/\sqrt{V}$

$$\lambda = \sqrt{\frac{150}{V}} * 10^{-8} \text{ cm} = \frac{1.23}{\sqrt{V}} \text{ nm}$$

Plug in known constants  
(lecture notes pp.8-9)

$$\lambda = \frac{1.23}{\sqrt{V + 10^{-6} V^2}} \text{ nm}$$

Make Einstein happy

## I.A.3 Photons/Electrons

### I.A.3.b Electron Velocity and Wavelength

$$\lambda = \frac{1.23}{\sqrt{V + 10^{-6} V^2}} \text{ nm} \quad (\text{includes relativistic effects})$$

$V$	$\lambda$ (nm)	$v$ ( $\times 10^{-10}$ cm/sec)	$v/c$
10,000	0.0122	0.585	0.195
50,000	0.0054	1.237	0.414
100,000	0.0037	1.644	0.548
1,000,000	0.0009	2.822	<b>0.941</b>

## TO SUMMARIZE THUS FAR:

Moving electrons behave as particles  
**and** waves (somewhat analogous to  
photons)

High voltage electrons move **fast** and  
have **very short** wavelengths

## *p-Flasher* Question

Which of the following best describes an electron that has been accelerated through a voltage difference of 100,000 volts?

- A) It moves faster than a speeding bullet (or superman)
- B) It moves slower than a speeding bullet (or superman)
- C) It moves a significant fraction of the speed of light
- D) It moves 1.6 times the speed of light

## I.A.3 Photons/Electrons

### KEY CONCEPTS

- Photons **and** electrons behave as particles **AND** waves
  - **Any** moving particle has a **wavelength** associated with it
  - **TEM: electrons** travel **very fast** (near speed of light) and have **very short** wavelengths
  - **Diffraction:** path of radiation is bent by ‘obstacles’
- 
- **Interference:** combination of diffracted and undiffracted waves
  - **Resolution:** ability to distinguish objects or object details
  - **Instrument resolution:** limited by wavelength of radiation

## I.A.3 Photons/Electrons

### I.A.3.c Interference / Diffraction / Coherence

## Ideal vs. Real Lenses

**Ideal lens:** images each **point** in an object as a **point** in the image plane

**Real lens:** images each **point** in an object as an **Airy disk** in the image plane

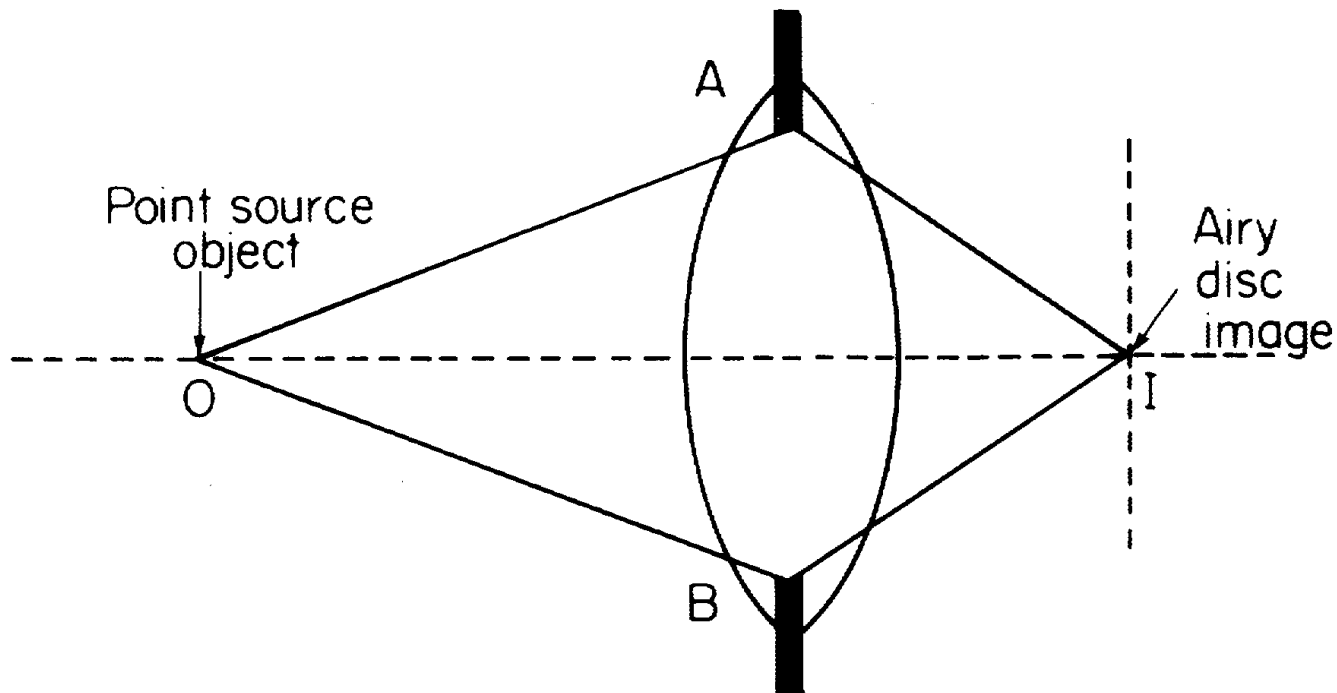


## I.A.3 Photons/Electrons

### I.A.3.c Interference / Diffraction / Coherence

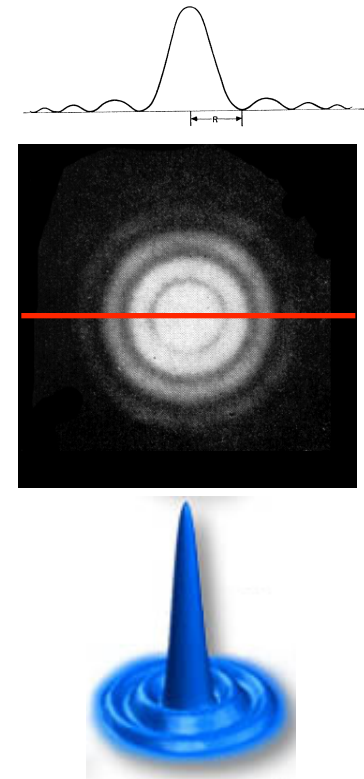
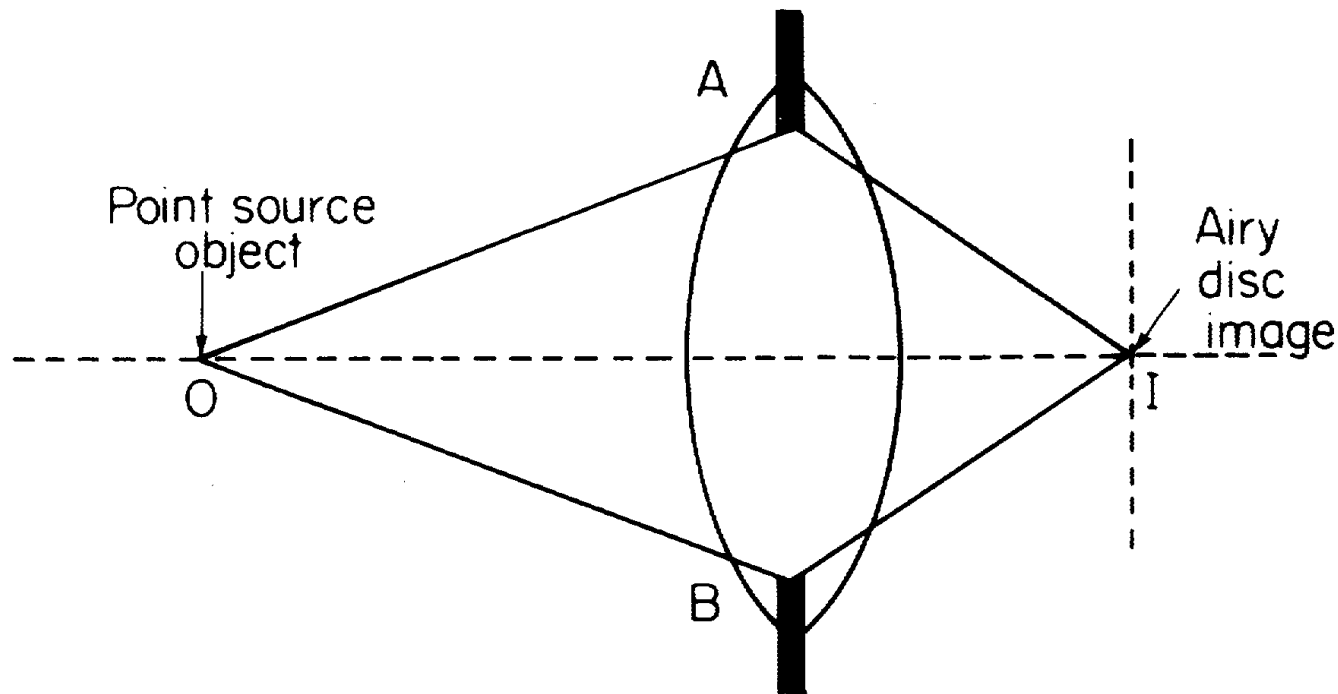
**IDEAL LENS:** takes each point in an object and represents it **exactly** as a point in the image.

**REAL LENS:** takes each object point and **spreads it out into a circular disk (Airy disk)** in the image plane.



## I.A.3 Photons/Electrons

### I.A.3.c Interference / Diffraction / Coherence



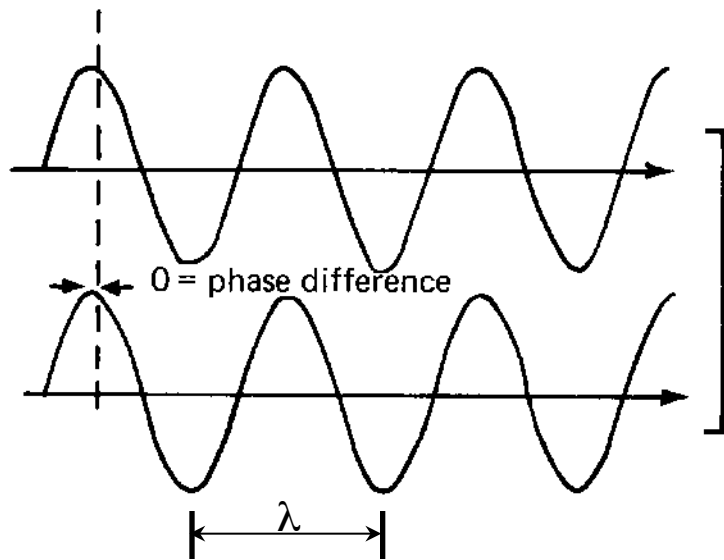
Airy disk image is caused by **interference of radiation diffracted** by the lens aperture.

**Size** (diameter) of Airy disk depends on the size of the aperture.

## I.A.3 Photons/Electrons

### I.A.3.c Interference / Diffraction / Coherence

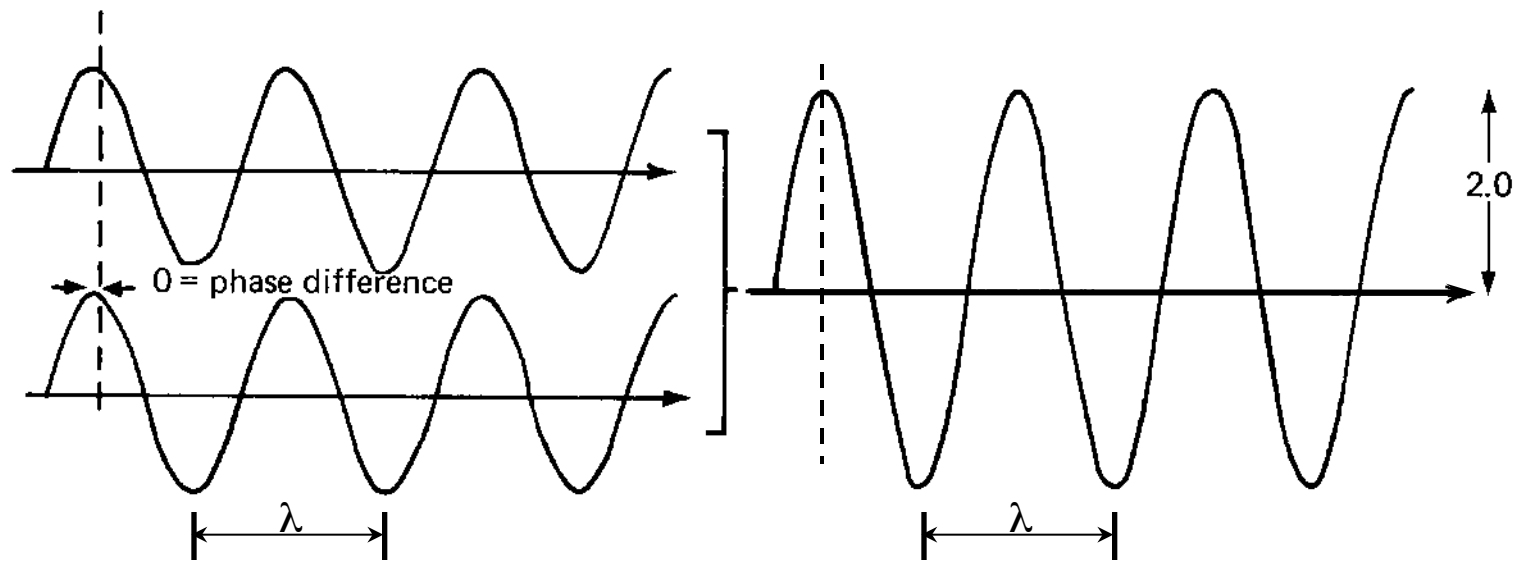
Effects of waves interfering (combining) with each other



## I.A.3 Photons/Electrons

### I.A.3.c Interference / Diffraction / Coherence

## Effects of waves interfering (combining) with each other

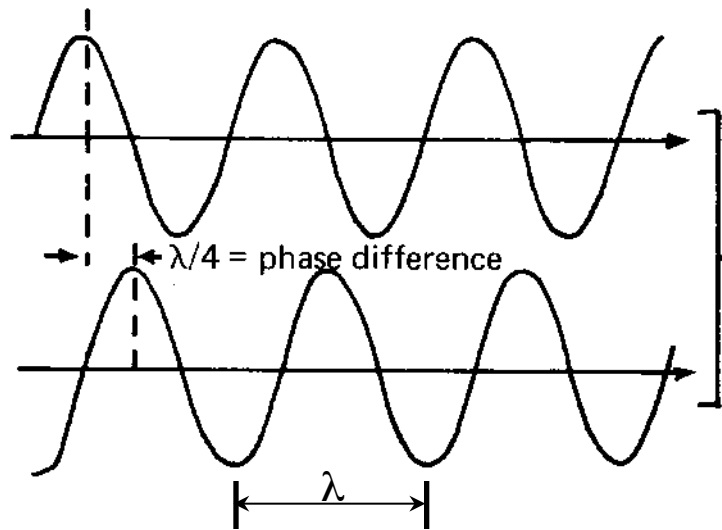


Total **constructive** interference  
"In phase"

## I.A.3 Photons/Electrons

### I.A.3.c Interference / Diffraction / Coherence

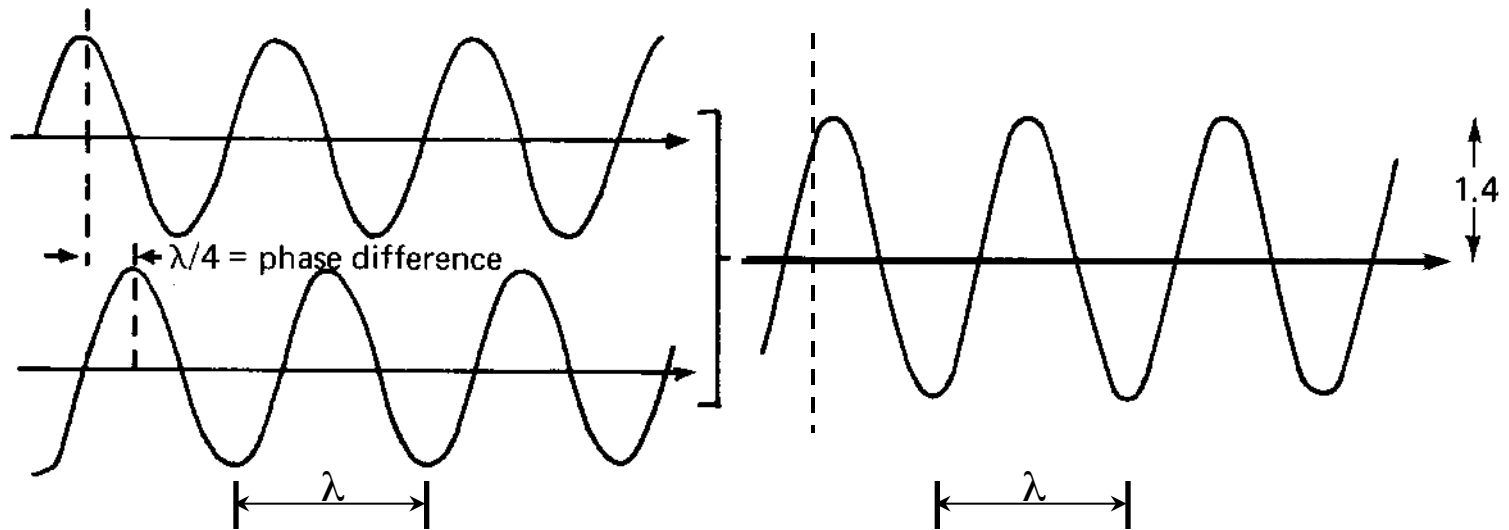
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## I.A.3 Photons/Electrons

### I.A.3.c Interference / Diffraction / Coherence

Effects of waves interfering (combining) with each other

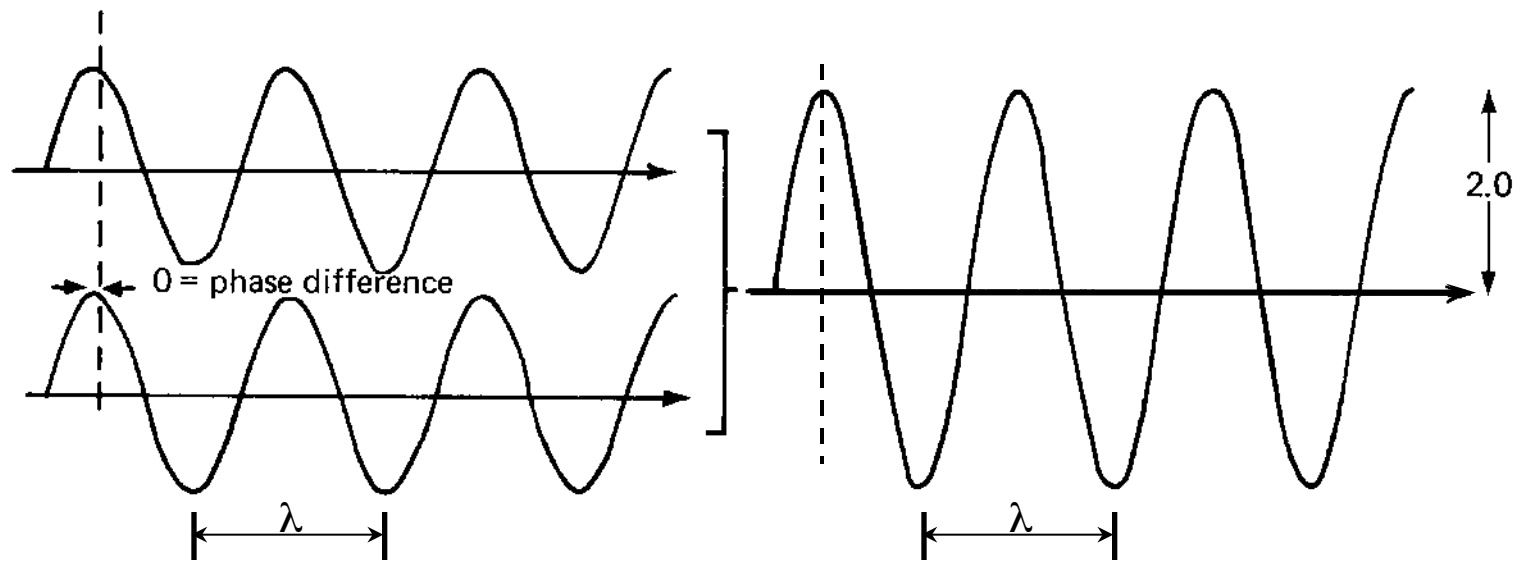


Partial **destructive** interference

## I.A.3 Photons/Electrons

### I.A.3.c Interference / Diffraction / Coherence

Effects of waves interfering (combining) with each other

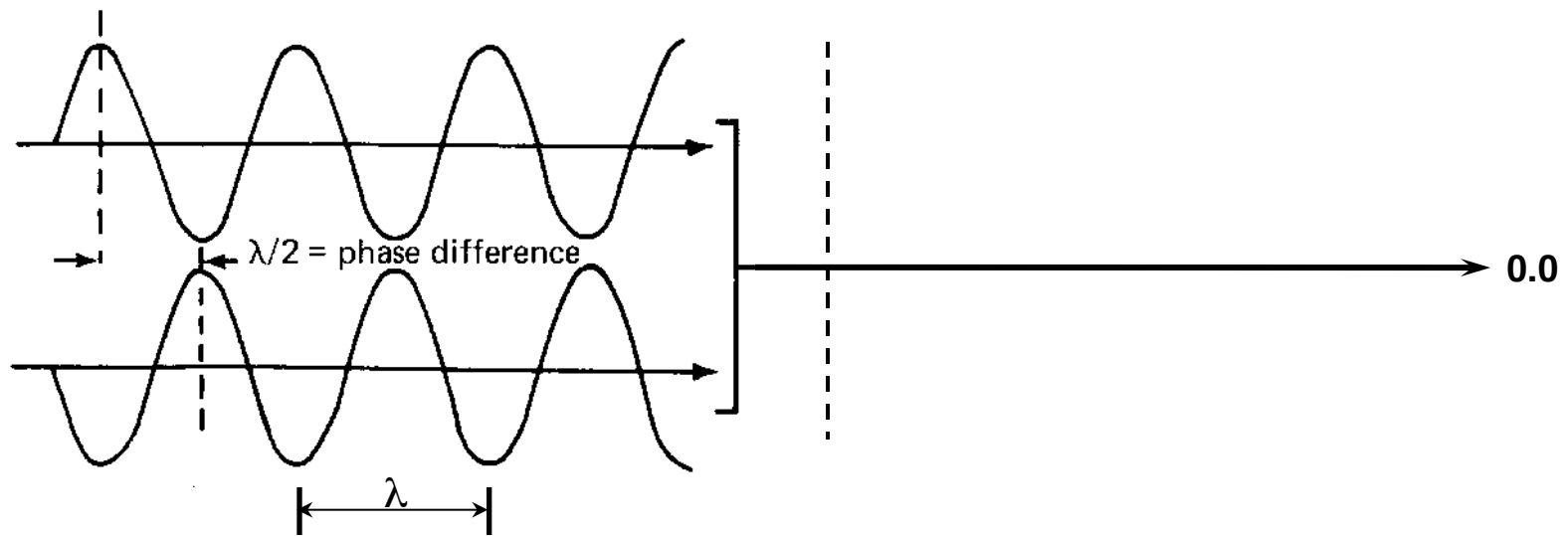


Total **constructive** interference  
“In phase”

## I.A.3 Photons/Electrons

### I.A.3.c Interference / Diffraction / Coherence

Effects of waves interfering (combining) with each other

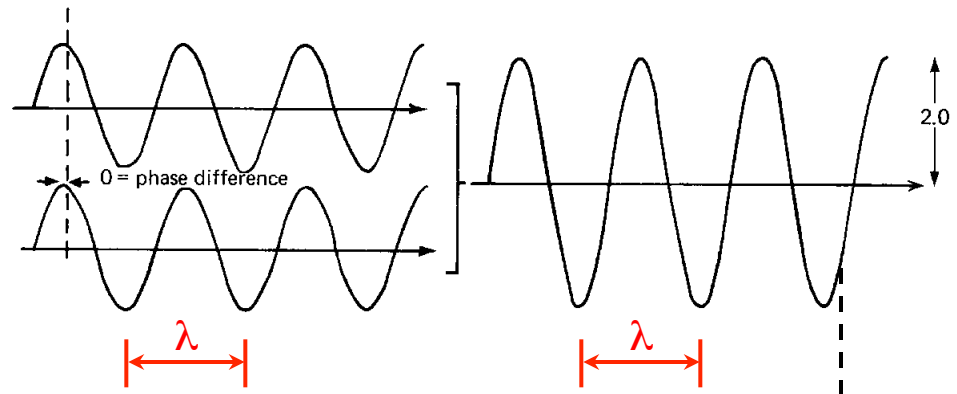


Total **destructive** interference  
“Out of phase”

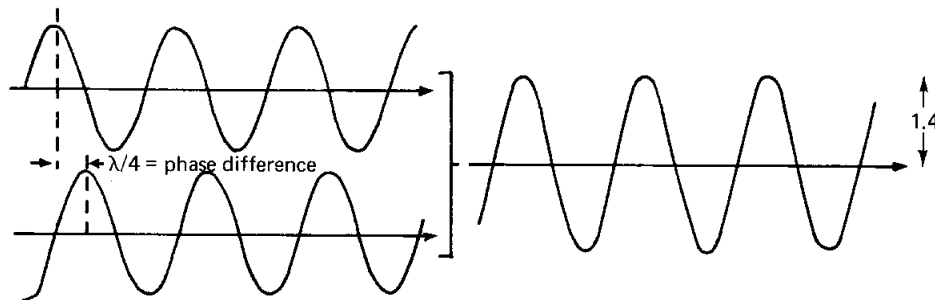


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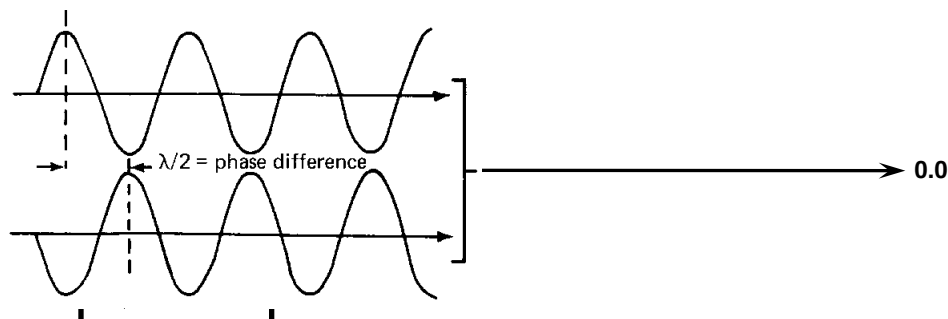
### Effects of waves interfering (combining) with each other



Total **constructive** interference  
"In phase"



Partial **destructive** interference

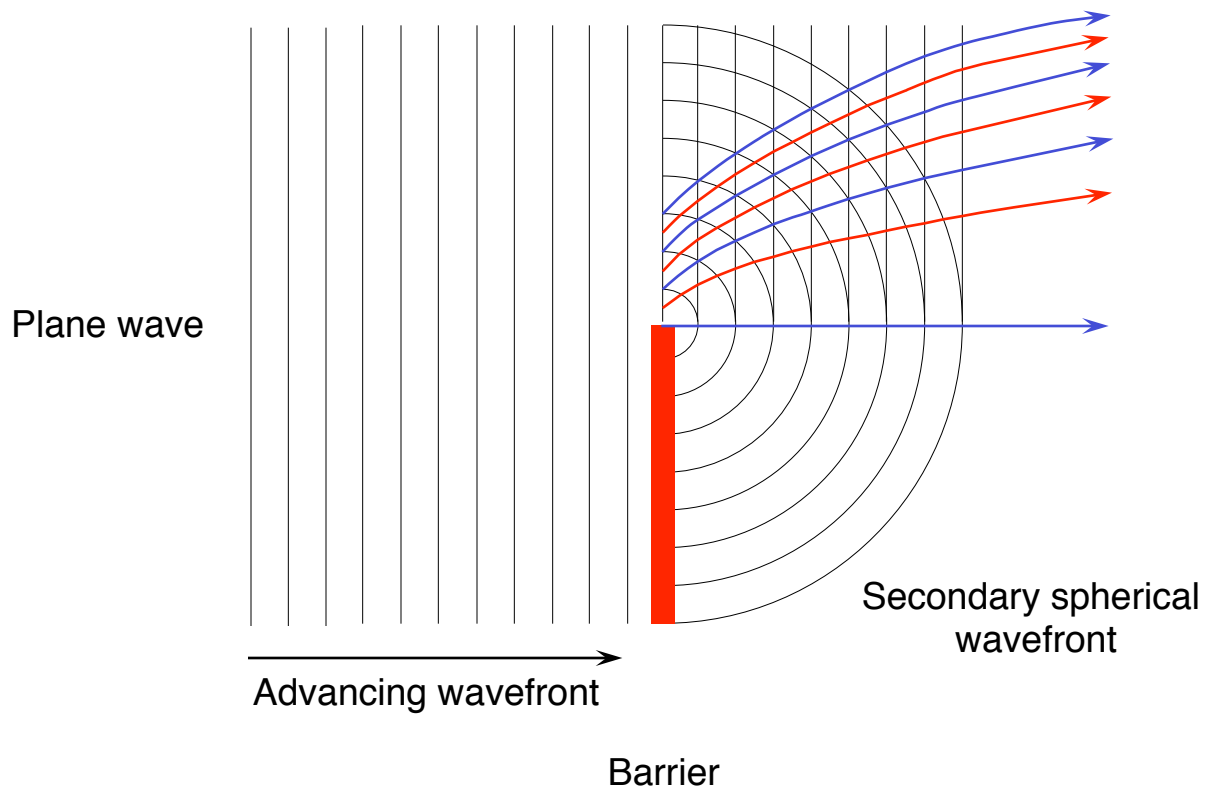


Total **destructive** interference  
"Out of phase"

## I.A.3 Photons/Electrons

### I.A.3.c Interference / Diffraction / Coherence

**Diffraction phenomena:** bending of the path of radiation passing close to an obstacle.



# I.A.3 Photons/Electrons

## I.A.3.c Interference / Diffraction / Coherence

**Diffraction phenomena:** bending of the path of radiation passing close to an obstacle.

